

INTERNATIONAL STANDARD

NORME INTERNATIONALE

Low resistance measurements – Methods and guidance

Mesures de faibles résistances – Méthodes et recommandations



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CONTENTS

FOREWORD	4
1 Scope	6
2 Normative references	6
3 Terms and definitions	6
4 Resistance measurement phenomena	7
4.1 General	7
4.2 Lead and contact resistance	7
4.3 Self-heating	9
4.4 Variation of resistance with temperature	10
4.5 Thermoelectric e.m.f.	12
4.6 Peltier effect	15
5 Methods of measurement	16
5.1 General	16
5.2 Four-wire resistance measurement	16
5.3 Offset compensation method	19
5.4 Current inversion method	22
5.5 Differential current inversion method	25
5.6 Short-term trigger method	28
6 Connecting the specimen	32
6.1 Resistors with lead wires for soldered assembly	32
6.1.1 Connecting leaded resistors in a test fixture	32
6.2 Resistors with solder terminations for surface mount assembly	33
6.2.1 Connecting SMD resistors on a test substrate	33
6.2.2 Connecting SMD resistors in a test fixture	35
7 Information to be given in the relevant component specification	36
Annex A (normative) Letter symbols and abbreviated terms	37
A.1 Letter symbols	37
A.2 Abbreviated terms	38
Annex B (informative) Test results of soldering pad with Kelvin connection for surface mount resistors	39
B.1 General	39
B.2 Test procedures	39
B.2.1 Test substrates	39
B.2.2 Test method	41
B.3 Measurement result and studies	42
Bibliography	45
Figure 1 – Resistance measurement using two-wire sensing	8
Figure 2 – Variation of resistance with temperature (random example)	10
Figure 3 – Resistances on a resistor with lead wires	11
Figure 4 – SMD chip resistor on a PCB	12
Figure 5 – Thermoelectric e.m.f.	13
Figure 6 – Thermocouples on a resistor with lead wires	14
Figure 7 – Resistance measurement affected by thermoelectric e.m.f.	15

Figure 8 – Four-wire resistance measurement	17
Figure 9 – Offset compensation method for resistance measurement.....	19
Figure 10 – Current and voltage in the offset compensation method	20
Figure 11 – Current inversion method for resistance measurement	22
Figure 12 – Current and voltage in the current inversion method.....	23
Figure 13 – Current and voltage in the differential current inversion method	26
Figure 14 – Example of resistor specimen.....	31
Figure 15 – Connecting leaded resistors in a test fixture	32
Figure 16 – Resistance of cylindrical copper lead wires	33
Figure 17 – Soldering pad of test substrate for Kelvin (four-point) connections	34
Figure 18 – Resistance of PCB conductor tracks with 35 µm copper thickness.....	35
Figure 19 – Example for connecting SMD resistors on a test fixture	36
Figure B.1 – Lengths of soldering pad.....	40
Figure B.2 – Position of voltage sense conductor.....	40
Figure B.3 – Thickness of the solder printing screen and position of sense line	43
Figure B.4 – Position of voltage-sensing line.....	43
Figure B.5 – Soldering pad length.....	44
Figure B.6 – Recommended soldering pad.....	44
Table 1 – Relative Seebeck coefficients of selected metals.....	13
Table A.1 – Letter symbols	37
Table B.1 – Thickness of solder printing screen.....	41
Table B.2 – Table of test conditions	42

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LOW RESISTANCE MEASUREMENTS – METHODS AND GUIDANCE

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International Standard IEC 62812 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
40/2665/FDIS	40/2671/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

LOW RESISTANCE MEASUREMENTS – METHODS AND GUIDANCE

1 Scope

Resistance measurements are typically compromised by a variety of phenomena, for example serial resistance in the measurement path, self-heating or non-ohmic properties. Whether the effect of such phenomena on a resistance measurement is acceptable or not depends on the magnitude of each effect in comparison to the resistance and to the required accuracy. Hence, the risk of erroneous resistance measurements increases with decreasing resistance and with a tightening of the permissible tolerance.

This document specifies methods of measurement and associated test conditions that eliminate or reduce the influence of adverse phenomena in order to improve the attainable accuracy of low-resistance measurements.

The methods described in this document are applicable for the individual measurements of the resistance of individual resistors, and also for resistance measurements as part of a test sequence. They are applied if prescribed by a relevant component specification, or if agreed between a customer and a manufacturer.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1, *Environmental testing – Part 1: General and guidance*

IEC 60115-1:2008, *Fixed resistors for use in electronic equipment – Part 1: Generic specification*

IEC 60294, *Measurement of the dimensions of a cylindrical component with axial terminations*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60115-1 and the following apply.

A list of used letter symbols and abbreviated terms is provided in Annex A.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
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3.1

electromotive force

e.m.f.

difference in potential that gives rise to an electric current